

Search Notes

Application/Control No.

10/065,552

Examiner

Wai-Sing Louie

Applicant(s)/Patent under
Reexamination

SAWADA ET AL.

Art Unit

2814

SEARCHED

Class	Subclass	Date	Examiner
438	14-18	11/15/2004	WSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
438/14,16,18		11/22/2005	WSL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
wafer charge measurement, liquid electrode, capacitance/voltage, C/V technique, carrier density, gallium	11/15/2004	WSL